

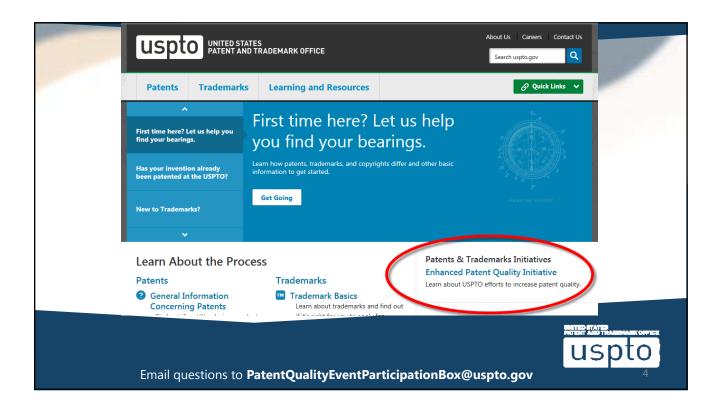
#### **Patent Quality Chat:**

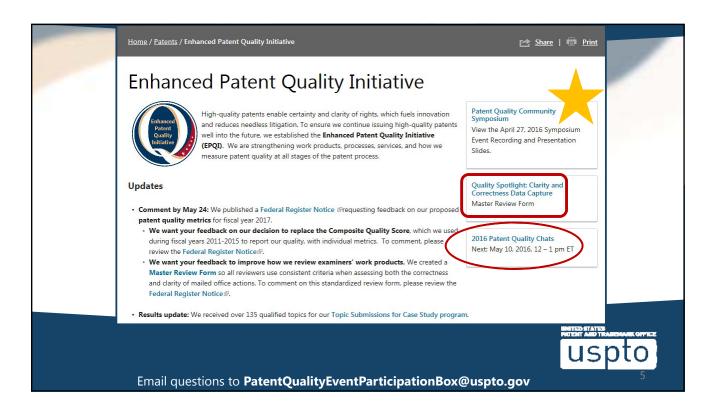
**Enhancing Examination Evaluation Using the Master Review Form (MRF)** 

Patent Quality Chat Webinar Series 2016 (5 of 11) May 10, 2016

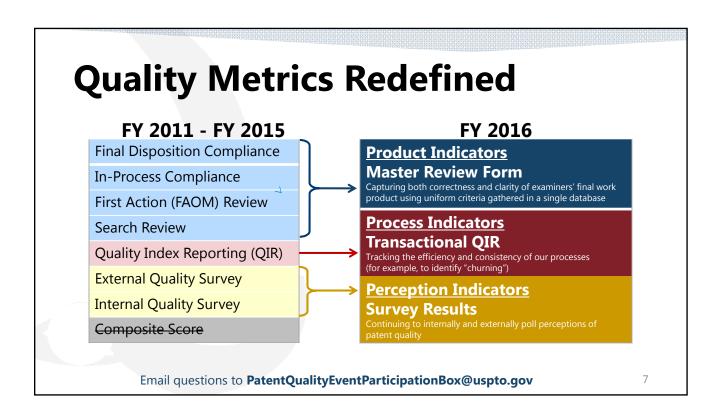


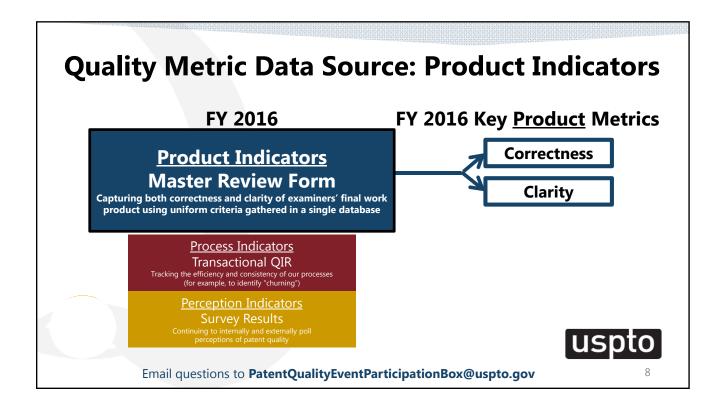


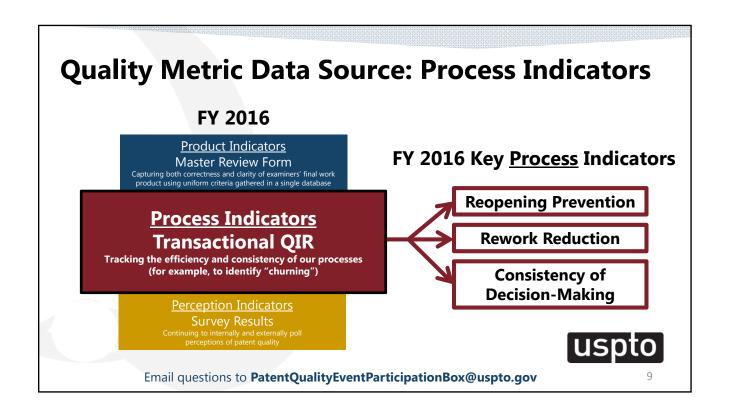


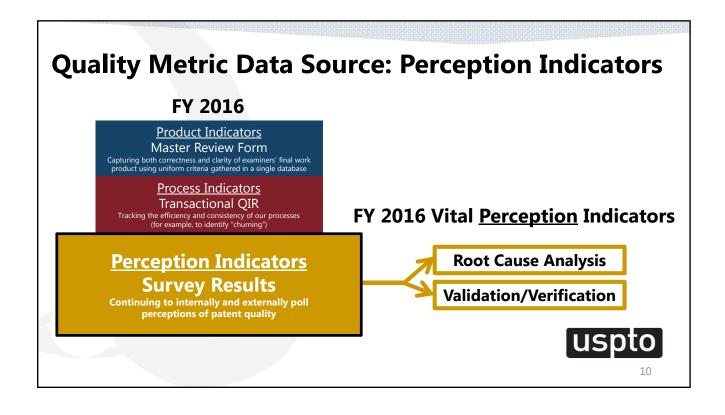












# Using EQS for Validating the Quality Metric

- Utilize the External Quality Survey as a snapshot of stakeholders' perceptions
- Assure alignment of the quality data underlying our metrics and our external stakeholders' perceptions
- Exploit the flexibility of the Master Review Form to capture data points that reflect patent quality

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# Clarity and Correctness Data Capture (CCDC) Program

- Designed to improve the data capture system to enable all reviewers to
  - Consistently document quality review data
  - Access quality review data using the same tool



Uses a tool called the Master Review Form or MRF

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#### **Master Review Form: Goals**

- To create a *single*, *comprehensive* tool that can be used by all areas of the Office to *consistently* review final work product
- To better collect information on the *clarity* and *correctness* of Office actions



To collect review results into a **single data warehouse** for more **robust analysis** 



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### **Master Review Form**

**VIEW THE Integrated Quality System (IQS)** 





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## **MRF: Overview Rejections Made**

#### Rejections made in Office action. Check all that apply. 35 U.S.C. 102 The MRF is a □ 35 U.S.C. 103 "Smart Form" ☐ 35 U.S.C. 112(a) – Written Description □ 35 U.S.C. 112(a) – Enablement Checking these boxes will ☐ 35 U.S.C. 112(b) – Vague and Indefinite Claim Language determine which sections of the form a reviewer will □ 35 U.S.C. 112(a)/(b) − 112(f) Related ☐ 35 U.S.C. 101 (Utility/Eligibility) ☐ Double Patenting (Statutory) Double Patenting (Nonstatutory obviousness-type) Email questions to PatentQualityEventParticipationBox@uspto.gov

## **MRF: Overview Rejections Omitted**

Were there any omitted rejections? Check all that apply	
<ul> <li>□ 35 U.S.C. 102</li> <li>□ 35 U.S.C. 103</li> <li>□ 35 U.S.C. 112(a) – Written Description</li> <li>□ 35 U.S.C. 112(a) – Enablement</li> </ul>	Reviewers will route to the various Omitted Rejections sections only if one or more of these boxes are
<ul> <li>□ 35 U.S.C. 112(b) – Vague and Indefinite Claim Language</li> <li>□ 35 U.S.C. 112(a)/(b) – 112(f) Related</li> <li>□ 35 U.S.C. 101 (Utility/Eligibility)</li> </ul>	The MRF is a
<ul><li>□ Double Patenting (Statutory)</li><li>□ Double Patenting (Nonstatutory obviousness-type)</li></ul>	"Smart Form"

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### **MRF: Evaluation of Search**

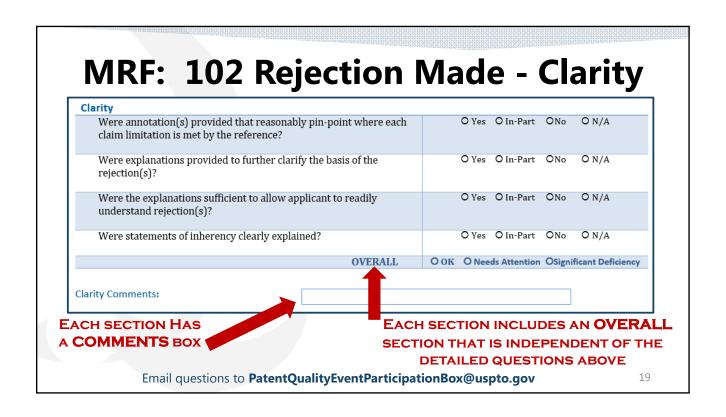
Search			
prrectness			
Was a classification search recorded by the examiner?	O Yes ONo		
Was an inventor name search recorded by the examiner?	O Yes ONo		
Was the examiner's text search logic recorded by the examiner?	O Yes ONo		
Did the reviewer conduct a search?	O Yes ONo		
Was prior art for the omitted rejection found using/in:	□Internet Search □IDS □PALM Inventor Name □892 □Classification search □ Text search □ Other □ N/A		

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# **MRF: 102 Rejection Made - Correctness**

Correctness				CERP
Claimed feature(s) are found in the prior art relied upon	O Yes	O In-Part	ONo	O N/A
Claim limitation(s) are properly matched to the prior art relied upon	O Yes	O In-Part	ONo	O N/A
Effective date of the reference applied as prior art is sufficient	O Yes	O In-Part	ONo	O N/A
Reliance on inherency is properly applied	O Yes	O In-Part	ONo	O N/A
The 102 determination was incorrect but the reference would serve as a 103.	O Yes	O In-Part	ONo	O N/A
Each claim rejected under 35 U.S.C. 102 has been properly addressed (i.e., "shotgun" rejection avoided)	O Yes	O In-Part	ONo	O N/A
Did not use incorrect form paragraph(s)	O Yes	O In-Part	ONo	O N/A
Were annotation(s) provided that reasonably pin-point where each claim limitation is met by the reference?	O Yes	O In-Part	ONo	O N/A

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MRF: 112(a) Written De	escription Made
Correctness	•
Claim limitations rejected as new matter do not have support in the specification	O Yes O In-Part ONo O N/A
Specification fails to describe claimed invention in sufficient detail that one skilled in the art can conclude the inventor was in possession of the claimed invention	O Yes O In-Part ONo O N/A
Correct form paragraph(s) used	O Yes O In-Part ONo O N/A
OVERALL	O OK O Needs Attention OSignificant Deficiency
Clarity  Does the office action clearly state that the rejection is based on the	O Yes O In-Part ONo O N/A
lack of written description?  Was subject matter purported to be unsupported matter clearly identified and discussed?	O Yes O In-Part ONo O N/A
OVERALL	O OK O Needs Attention OSignificant Deficience

# **MRF: Reply to Applicant**

Were all grounds of rejection clearly presented in the Office action and was the examiner's position fully developed?	O Yes O In-Part ONo O N/A
Were all of applicant's arguments addressed in the Office action (whether examiner's position was correct or not) including arguments with respect to art still relied upon?	O Yes O In-Part ONo O N/A
If applicant's response should have been found persuasive to overcome the rejection(s), did the examiner drop all of the corresponding rejection(s) in the Office action?	O Yes O In-Part ONo O N/A
Was the case as a whole allowable based on the record?	O Yes O In-Part ONo O N/A
Were the affidavits/declarations evaluated sufficiently?	O Yes O In-Part ONo O N/A

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### **Complete Master Review Form**

To view the complete MRF:

http://www.uspto.gov/sites/default/files/ documents/MRF.pdf





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## **Quality Metrics**

- Federal Register Notice published on March 25, with comments due May 24
  - Requesting feedback on:
    - Decision to replace Composite Quality Score with individual metrics
    - How to objectively measure patent examination quality
    - Standardized Master Review Form



Quality Metrics website: <a href="http://www.uspto.gov/patent/initiatives/quality-metrics">http://www.uspto.gov/patent/initiatives/quality-metrics</a>
Contact Us: <a href="mailto:QualityMetrics2017@uspto.gov">QualityMetrics2017@uspto.gov</a>



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# Let's Chat about the Master Review Form (MRF)

#### **Marty Rater**

Chief Statistician
Office of Patent Quality Assurance (OPQA)

#### **Sandie Spyrou**

Supervisory Review Quality Assurance Specialist Office of Patent Quality Assurance (OPQA)



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# Thank you for joining us today!

Patent Quality Chat Webinar Series 2016 (5 of 11) May 10, 2016



### **Next Patent Quality Chat:**

Tuesday, June 14<sup>th</sup> eCommerce Modernization (eMod): Improving the Electronic Patent Application Process



